

LED WAFER/CHIP PROBER MODEL 58153

Chroma 58153 LED Wafer/Chip Prober System is a precision machine specifically designed for probing applications involving LED or Laser Diode wafers/chips from 2 to 8 inch. With high resolution camera, video capture card, and image processing software, 58153 prober system performs accuracy chip/die positioning and high speed automatic measurement. In addition, automatic Z axis height compensation, and automatic adjustment for chip horizontal position, 30 degree \varnothing rotation stage, 58153 can improve the accuracy and stability of wafer/chip testing significantly.

Chroma 58153 is constructed with ultra high purity ball screws, high precision linear motion guide, 4-axis high force, beryllium copper and tungsten probe needles, and high spindle micro stepping motors, all within a computer designed platform to minimize vibration and acoustic noise. The other remarkable record of 58153 is index time, it can be held within 100ms from one chip/die location to the next.

58153 prober systems can be integrated with Chroma 58151 PXI LED Test System for optical and electrical testing purposes. The resulting test throughput is significantly higher than any other tester/prober combination in the world. The advantages to customers are minimizing the test cost and maximizing the production capacity of clean room.

Key Features

- 100 ms index time
- Performing scanning tests forth and back from center to one side and return to center for another side.
- Automatically skip around the defective chips
- Easy to use software interface
- 30 degree \varnothing rotation range
- Auto chip horizontal adjustment
- Auto compensation for Z axis height
- Height adjustable probe platform
- Wizard-Guided Steps
- Click-on-image setup navigation
- User defined, dynamically displayed colored maps and test data

Probe

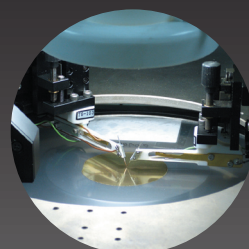
- Up to four inkers Accepted
- Easy On-Head Probe Connection Changes
- Accommodates Dual Edge Sensing
- Individual Probe X, Y, and Z adjustments

Software

- Wizard-Guided Steps
- Click-on-image setup navigation
- User defined, dynamically displayed colored maps and binning
- Test Result Maps
- Real Time Wafer mapping

Tester Supported

- Chroma 58151 LED Test System
- CM LED Tester
- Wei min LED Tester



58153 Probe



58153 Software



58151 LED Test System



Chroma

SPECIFICATIONS

Chuck Size	6 in., maximum 8 in.
Suitable Wafer	2-4 in. undiced wafer 2-4 in. diced wafer
PC Equipment	Industrial PC (Pentium 4 - 2.8GHz) Windows 2000
CCD	Resolution 1024 x 768 Pixel Gray scale CCD (256 scales)
Stroke	X axis 300mm Y axis 300mm Ø15%
Positioning Analysis	X axis 1 µm Y axis 1 µm Z axis 1 µm Ø axis 0.009 degree
Machinery Equipment	Semiconductor-grade Ball Screws High Precision Linear Motion Guide 4-Axis High Force, High Spindle Micro Stepping Motor 80 ms machine moving speed during probing
Probe Material	Tungsten, Steel Tungsten Carbide, Cooper
Weight	400kg
Power Requirement	110 VAC 50/60Hz
Dimension	800mm (L) x 900mm (W) x 1300mm (H)
Accessories	Microscope LCD, Keyboard, Mouse Industrial PC CCD, Lens Probe Station 3-Color Rotating Warning Light Beacon

ORDERING INFORMATION

58153 : LED Wafer/Chip Prober

Developed and Manufactured by :

CHROMA ATE INC.

致茂電子股份有限公司

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